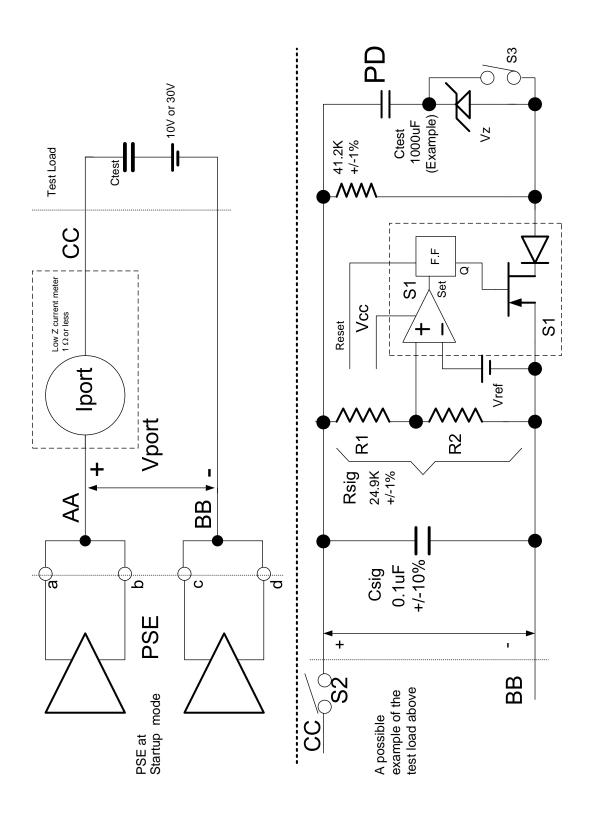
+	+
	802-3/802.3 REVISION REQUEST 1165
+==	==============++
DATE:	30th March, 2005
NAME:	Yair Darshan
COMPANY/AFFILIATION:	PowerDsine
E-MAIL:	yaird@powerdsine.com
REQUESTED REVISION:	
STANDARD:	IEEE Std. 802.3af-2003
CLAUSE NUMBER:	
CLAUSE TITLE:	
DDODOGED DEVICEOU ME	
PROPOSED REVISION TE	XT:
Paragraph 33C.1.4, t	he text after figure 33C.3.
Change from "3. The	capacitive load value is chosen to emulate a short-
circuit condition for more than 75ms"	
To "3. The capacitiv	e load value Ctest is chosen to emulate inrush cur-
rent during a startup mode condition. Ctest is chosen larger than that allowable for Cpd to ensure the PSE stays in Inrush current limit for	
	t>Iinrush*Tlim/Vport.
Figure 33C.3:	
Change Cpd to Ctest.	
change opa co coesc.	
RATIONALE FOR REVISION:	
33C.1.4 is meant to	illustrate how to measure the parameters Inrush and
its time duration (S	ee item (a) in the beginning of paragraph 33C.1.4.)
and is required to successfully support the startup mode where the PSE is	
driving a capacitive	load, Cpd.
mbo figures alternies of	toot_1000vE /which
	test=1000uF (which was Cpd=1000uF) in the example
causes confusion with the specified maximum Cpd which is 180uF per 33.3.5.3.	
IMPACT ON EXISTING N	ETWORKS:
No impact on current	hardware. It is all informative, at the informative
section.	



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